

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/586,108	GAUDREAU, JEAN-ETIENNE	
Examiner	Art Unit	
CHRIS H. CHU	2874	

OFAROUER					
SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
applicant's cited references	12/11/2008	/CC/	
text search	12/11/2008	/CC/	
class 349, further limiting with text	12/11/2008	/CC/	